

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/617,171	JEONG, KI-TAG
Examiner	Art Unit	
Tianjie Chen	2627	

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>